Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/668,881	GORRELL ET AL.
Examiner	Art Unit
Chris C. Chu	2016

SEARCHED					
Class	Subclass	Date	Examiner		
257	729 and 778	6/21/2005	C.C.		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	6/21/2005	C.C.
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